

Conference Digest

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Conference on Precision Electromagnetic Measurements

16-21 June 2002

Conference Digest

2002 Conference on Precision Electromagnetic Measurements

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Canada
16-21, June 2002

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PREFACE

It is indeed an honor and a privilege for me to welcome you to Canada's Capital for the 2002 Conference on Precision Electromagnetic Measurements (CPEM 2002). This is the twenty-third in this biennial conference series. CPEM was first held in Boulder, USA, in 1958. NRC is pleased to host CPEM 2002 for the third time in Ottawa. The international nature of CPEM was broadened to allow alternating the locations between North America and other parts of the world. The North American Conferences, in turn, rotate between Boulder, Gaithersburg, and Ottawa. As part of this rotation, NRC is privileged to host CPEM every twelve years.

CPEM is devoted to topics related to electromagnetic measurements at the highest accuracy levels. These cover the frequency spectrum from DC through the optical region. As the maintenance of some of the highest accuracy electrical standards was converted to quantum devices, topics that relate the electrical standards to the fundamental constants have become part of CPEM. The very latest advances in all these areas are covered in both invited and submitted papers.

About three hundred papers have been accepted for both oral and poster presentations. The authors of the papers are from more than thirty countries. The Organizing Committee would like to acknowledge the increasing number of submissions and participants from developing countries. We hope this trend will continue. We are also pleased to welcome ten talented young metrologists who have been awarded funding assistance to attend the conference, through the "Young Scientist Program".

On behalf of the Organizing Committee, I would like to thank all the authors, the sponsors and the exhibitors for their valuable contributions to this conference. I wish you all, participants and accompanying persons, a pleasant stay in the beautiful city of Ottawa.

Eddy So
Conference Chair

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